

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/751,418	TANAKA ET AL.	
	Examiner EDMUND H. LEE	Art Unit 1732	

SEARCHED

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
264	252,275	12/15/2005	EHL
	267		